Searcn Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/688,684	YI, SEUNG HYUN	
Examiner	Art Unit	
Hai L. Nguyen	2816	

	SEAR	CHED	
Class	Subclass	Date	Examiner
327	141,147, 149,150, 153,155, 156	4/18/2005	HLN
	158,159		
V	161-163		
331	1A,1R		
	DIG.2		
V	18,25	<b>V</b>	
375	373,375	4/19/2005	
	376	)	V
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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(INCLUDING SE	ARCH S	TRATEGY	)
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